

M66282FP

8192 × 8-Bit Line Memory

REJ03F0255-0200 Rev.2.00 Sep 14, 2007

Description

The M66282FP is high speed line memory that uses high performance silicon gate CMOS process technology and adopts the FIFO (First In First Out) structure consisting of 8192 words × 8 bits.

The M66282FP, performing reading and writing operations at different cycles independently and asynchronously, is optimal for buffer memory to be used between equipment of different data processing speeds.

Features

Memory configuration: 8192 words × 8 bits (dynamic memory)

High speed cycle: 25 ns (Min)
High speed access: 18 ns (Max)
Output hold: 3 ns (Min)

Reading and writing operations can be completely carried out independently and asynchronously

• Variable length delay bit

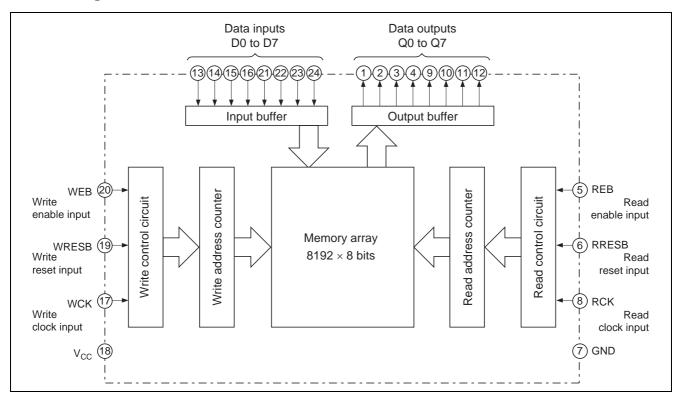
• Input/output: TTL direct connection allowable

• Output: 3 states

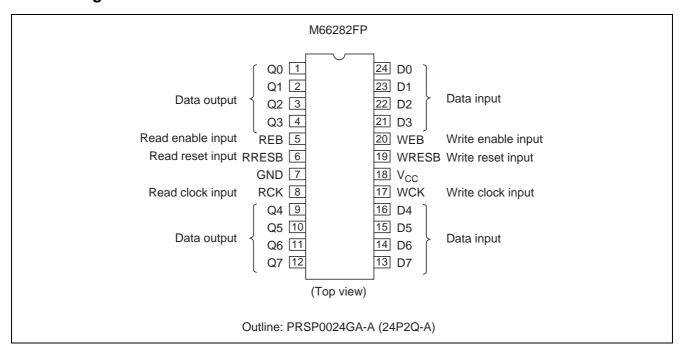
Application

Digital copying machine, laser beam printer, high speed facsimile, etc.

Block Diagram



Pin Arrangement



Absolute Maximum Ratings

 $(Ta = 0 \text{ to } 70^{\circ}\text{C}, \text{ unless otherwise noted})$

Item	Symbol	Ratings	Unit	Conditions
Supply voltage	V _{CC}	−0.3 to +4.6	V	Value based on the GND pin
Input voltage	VI	-0.3 to $V_{CC} + 0.3$	V	
Output voltage	Vo	-0.3 to $V_{CC} + 0.3$	V	
Power dissipation	Pd	300	mW	
Storage temperature	Tstg	-55 to 150	°C	

Recommended Operating Conditions

Item	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{CC}	2.7	3.15	3.6	V
Supply voltage	GND	_	0	_	V
Operating temperature	Topr	0	_	70	°C

Electrical Characteristics

(Ta = 0 to 70°C, V_{CC} = 2.7 to 3.6 V, GND = 0 V, unless otherwise noted)

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Item	Symbol	Min	Тур	Max	Unit	Test Conditions	
High-level input voltage	V _{IH}	2.0	_	_	V		
Low-level input voltage	V _{IL}	_	_	0.8	V		
High-level output voltage	V _{OH}	V _{CC} - 0.4	_	_	V	$I_{OH} = -4 \text{ m}$	A
Low-level output voltage	V _{OL}	_	_	0.4	V	I _{OL} = 4 mA	
High-level input current	Іін	_		1.0	μΑ	V _I = V _{CC}	WEB, WRESB, WCK, REB, RRESB, RCK, D0 to D7
Low-level input current	I _{IL}	_		-1.0	μΑ	V _I = GND	WEB, WRESB, WCK, REB, RRESB, RCK, D0 to D7
Off-state high-level output current	l _{OZH}	_	_	5.0	μА	Vo = V _{CC}	
Off-state low-level output current	l _{OZL}	_	_	-5.0	μА	Vo = GND	
Average supply current during operation	Icc	_	_	70	mA	$V_I = V_{CC}$, GND, Output open t_{WCK} , $t_{RCK} = 25$ ns	
Input capacitance	Cı	_	_	10	pF	f = 1 MHz	
Off-time output capacitance	Co	_	_	15	pF	f = 1 MHz	

Function

When write enable input WEB is set to "L", the contents of data inputs D0 to D7 are read in synchronization with a rising edge of write clock input WCK to perform writing operation. When this is the case, the write address counter is also incremented simultaneously.

When WEB is set to "H", the writing operation is inhibited and the write address counter stops.

When write reset input WRESB is set to "L", the write address counter is initialized.

When read enable input REB is set to "L", the contents of memory are output to data outputs Q0 to Q7 in synchronization with a rising edge of read clock input RCK to perform reading operation. When this is the case, the read address counter is incremented simultaneously.

When REB is set to "H", the reading operation is inhibited and the read address counter stops. The outputs are placed in a high impedance state.

When read reset input RRESB is set to "L", the read address counter is initialized.



Switching Characteristics

(Ta = 0 to 70°C, V_{CC} = 2.7 to 3.6 V, GND = 0 V, unless otherwise noted)

Item	Symbol	Min	Тур	Max	Unit
Access time	t _{AC}		_	18	ns
Output hold time	t _{OH}	3	_		ns
Output enable time	t _{OEN}	3	_	18	ns
Output disable time	todis	3	—	18	ns

Timing Requirements

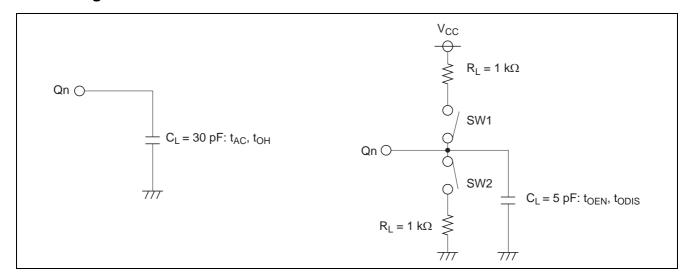
(Ta = 0 to 70°C, V_{CC} = 2.7 to 3.6 V, GND = 0 V, unless otherwise noted)

Item	Symbol	Min	Тур	Max	Unit
Write clock (WCK) cycle	t _{WCK}	25		_	ns
Write clock (WCK) "H" pulse width	twckh	11	_	_	ns
Write clock (WCK) "L" pulse width	t _{WCKL}	11	_	_	ns
Read clock (RCK) cycle	t _{RCK}	25	_	_	ns
Read clock (RCK) "H" pulse width	t _{RCKH}	11	—	_	ns
Read clock (RCK) "L" pulse width	t _{RCKL}	11	_	_	ns
Input data setup time for WCK	t _{DS}	7	_	_	ns
Input data hold time for WCK	t _{DH}	3	_	_	ns
Reset setup time for WCK/RCK	t _{RESS}	7	_	_	ns
Reset hold time for WCK/RCK	t _{RESH}	3	_	_	ns
Reset non-selection setup time for WCK/RCK	t _{NRESS}	7	_	_	ns
Reset non-selection hold time for WCK/RCK	t _{NRESH}	3	_	_	ns
WEB setup time for WCK	t _{WES}	7	_	_	ns
WEB hold time for WCK	t _{WEH}	3	_	_	ns
WEB non-selection setup time for WCK	t _{NWES}	7	_	_	ns
WEB non-selection hold time for WCK	t _{NWEH}	3	_	_	ns
REB setup time for RCK	t _{RES}	7	_	_	ns
REB hold time for RCK	t _{REH}	3	_	_	ns
REB non-selection setup time for RCK	t _{NRES}	7	_	_	ns
REB non-selection hold time for RCK	t _{NREH}	3	_	_	ns
Input pulse up/down time	tr, tf	_	_	20	ns
Data hold time*	t _H	_	_	20	ms

Notes: Perform reset operation after turning on power supply.

For 1 line access, the following conditions must be satisfied: WEB high-level period \leq 20 ms - 8192 • t_{WCK} - WRESB low-level period REB high-level period \leq 20 ms - 8192 • t_{RCK} - RRESB low-level period

Switching Characteristics Measurement Circuit



Input pulse level: 0 to 3 V
Input pulse up/down time: 3 ns
Judging voltage Input: 1.3 V

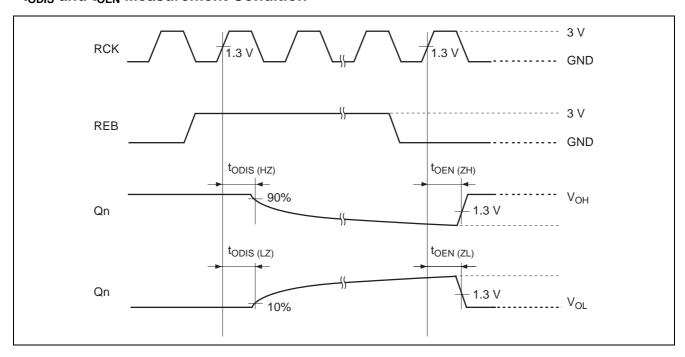
Output: 1.3 V (However, $t_{ODIS\;(LZ)}$ is judged with 10% of the output amplitude, while $t_{ODIS\;(HZ)}$ is

judged with 90% of the output amplitude.)

Load capacitance C_L includes the floating capacity of connected lines and input capacitance of probe.

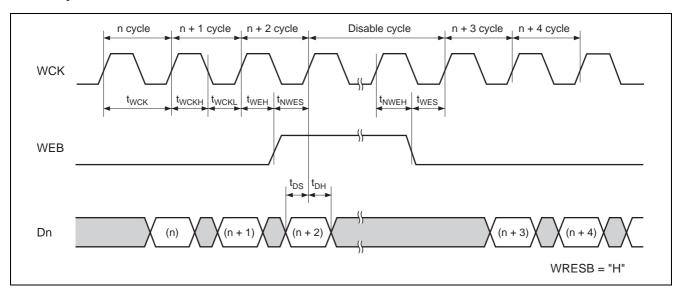
Item	SW1	SW2
t _{ODIS (LZ)}	Close	Open
t _{ODIS (HZ)}	Open	Close
t _{OEN (ZL)}	Close	Open
t _{OEN (ZH)}	Open	Close

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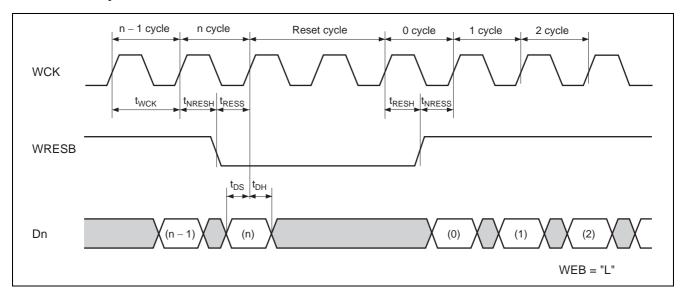


Operation Timing

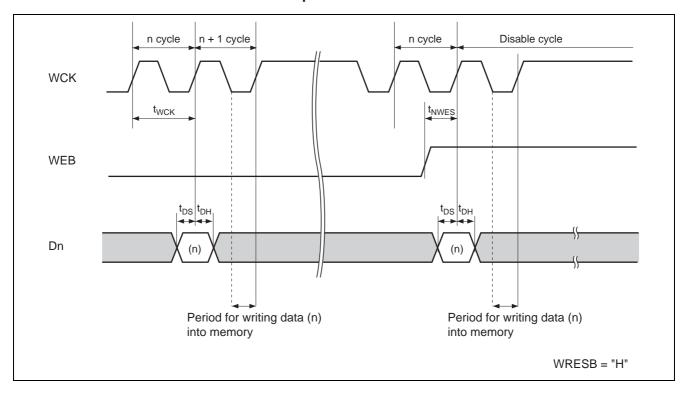
Write Cycle



Write Reset Cycle



Matters that Needs Attention when WCK Stops

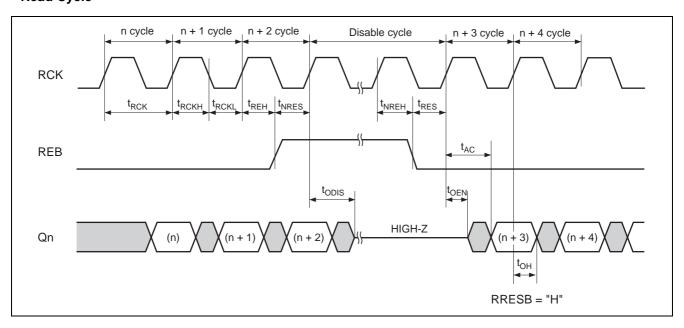


Input data of n cycle is read at the rising edge after WCK of n cycle and writing operation starts in the WCK low-level period of n + l cycle. The writing operation is complete at the falling edge after n + l cycle.

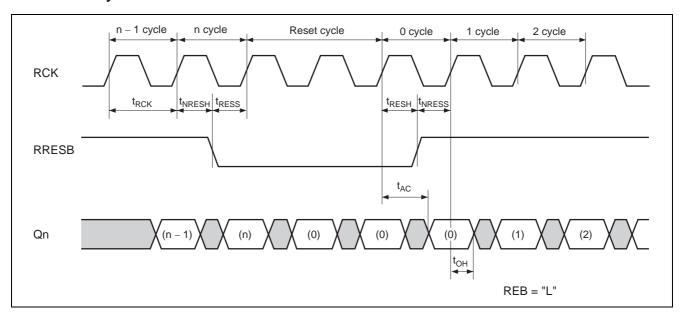
To stop reading write data at n cycle, enter WCK before the rising edge after n+1 cycle.

When the cycle next to n cycle is a disable cycle, WCK for a cycle requires to be entered after the disable cycle as well.

Read Cycle



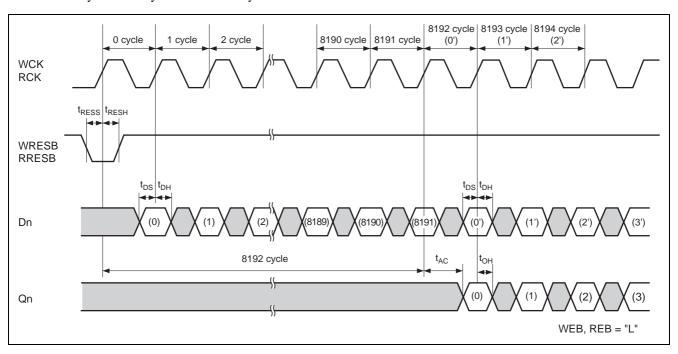
Read Reset Cycle



Variable Length Delay Bit

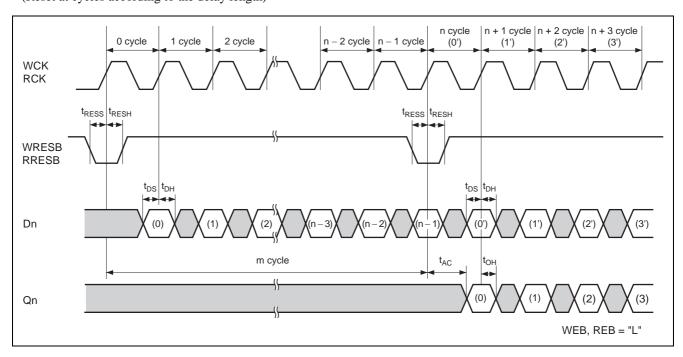
1 Line (8192 Bits) Delay

Input data can be written at the rising edge of WCK after write cycle and output data is read at the rising edge of RCK before read cycle to easily make 1 line delay.



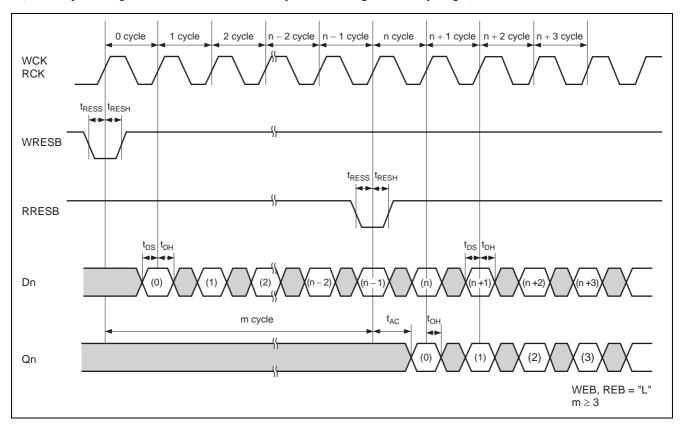
n-bit Delay Bit

(Reset at cycles according to the delay length)



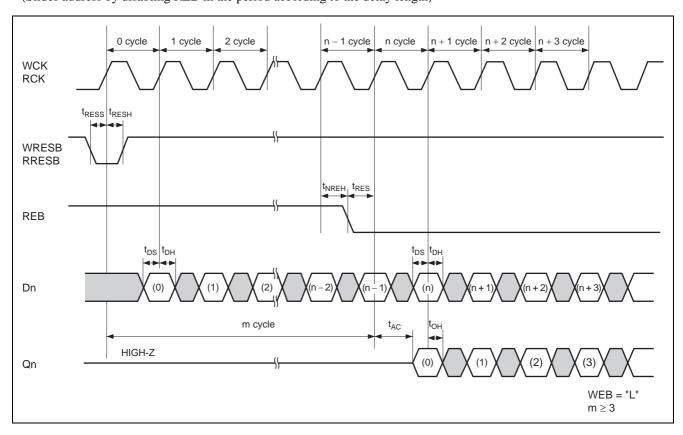
n-bit Delay 2

(Slides input timings of WRESB and RRESB at cycles according to the delay length)



n-bit Delay 3

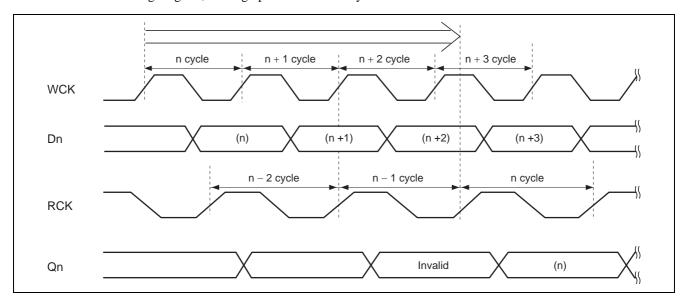
(Slides address by disabling REB in the period according to the delay length)



Reading Shortest n-cycle Write Data "n"

(Reading side n - 1 cycle starts after the end of writing side n - 1 cycle)

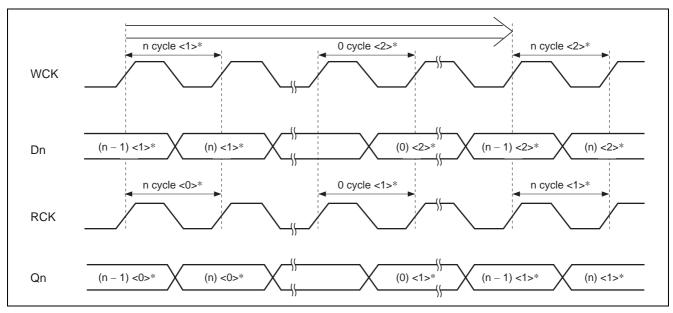
When the reading side n-1 cycle starts before the end of the writing side n+1 cycle, output Qn of n cycle is made invalid. In the following diagram, reading operation of n-1 cycle is invalid.



Reading Longest n-cycle Write Data "n": 1 Line Delay

(When writing side n-cycle <2>* starts, reading side n cycle <1>* then starts)

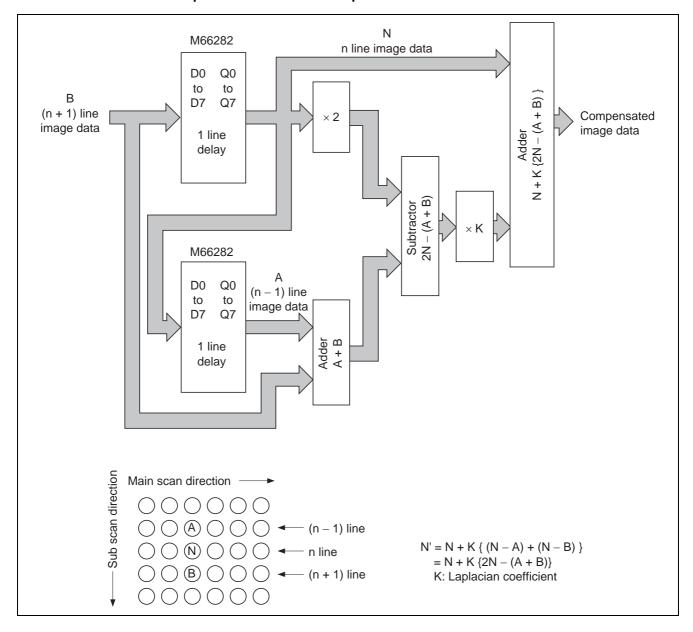
Output Qn of n cycle <1>* can be read until the start of reading side n cycle <1> and the start of writing side n cycle <2>* overlap each other.



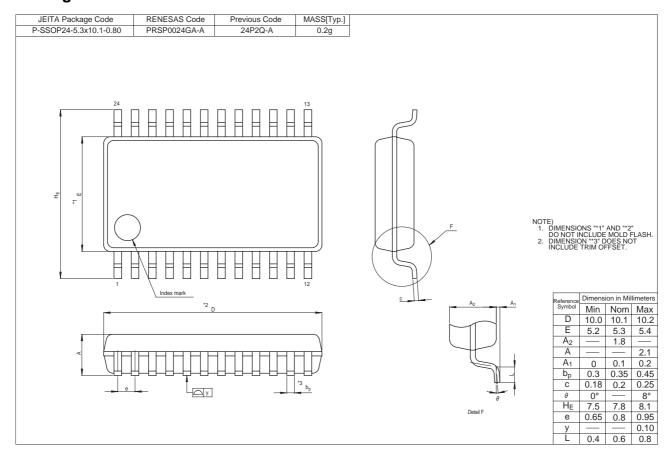
Note: <0>*, <1>* and <2>* indicate value of lines.

Application Example

Sub Scan Resolution Compensation Circuit with Laplacian Filter



Package Dimensions



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